

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE					ATTY. DOCKET NO. ARC9-2000-0066-US2	SERIAL NO. 10/765, Not yet assigned 545								
<b>LIST OF PRIOR ART CITED BY APPLICANT</b> (Use several sheets if necessary)					APPLICANT BAGLIN, John E.E.									
					FILING DATE Filed Herewith	GROUP 2829 not yet assigned								
U.S. PATENT DOCUMENTS														
EXAMINER INITIAL		DOCUMENT NUMBER		DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE						
<i>LAC</i>	A	5	0	7	9	6	6	2	01/07/92	Kawakami et al.	/	/		
		5	5	5	0	1	0	1	08/27/96	Nagata et al.	/	/		
		6	0	7	7	6	1	8	06/20/00	Sakamina et al.	/	/		
<i>LAC</i>		6	3	1	7	3	0	2	11/13/01	Van Kesteren et al.				
FOREIGN PATENT DOCUMENTS														
		DOCUMENT NUMBER		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION						
								YES      NO						
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)														
	B	Yimin Guo et al. in "Low Fringe-Field and Narrow-Track MR Heads", IEEE Transactions on Magnetics, Vol. 33, No. 5, Sept. 1997, pp. 2827-9.												
	C	G.J. Athas et al. "Focused Ion Beam System for Automated MEMS Prototyping and Processing", Proc. SPIE - Int. Soc. Opt. Eng. (USA), Vol. 3223, 1997, pp. 198-207.												
	D	Charles Partee et al., "Off-Track Response Versus Shield Width at the ABS for MR Heads", IEEE Transactions on Magnetics (USA), Vol. 33, No. 5, Pt. 1, Sept. 1997, pp. 2887-9.												
	E	W.M. Kaminsky et al., "Patterning Ferromagnetism in Ni <sub>80</sub> Fe <sub>20</sub> Films via 30 keV Ga <sup>+</sup> on Irradiation", Applied Physics Letters, March 30 2000.												
EXAMINER <i>LAC</i>				DATE CONSIDERED <i>7/8/4</i>										
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.														